

# Search Notes



Application/Control No.

09/829,151

Examiner

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Applicant(s)/Patent under Reexamination

YOUNG, ALAN

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	1	2005 updating 3/06	DM
	7		
	8		
	9		
	10		
706	12		
	46		
	52		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	3/06	DM
1. Patent		
2. PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		